



Advances in Machine Condition Monitoring and Fault Diagnosis

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Message from the Guest Editors

Condition monitoring and fault diagnosis have demonstrated its effectiveness in improving the operation, maintenance, availability and therefore economic return of machines. They will play a more vital role in the future industrial production process with the rapid development of modern machinery industry. That requests the condition monitoring and fault diagnosis techniques to be more reliable and efficient in practical use. However, this is challenged by the fact that modern machines are becoming more complex in structure, larger in size, and operate under harsher loading and operational conditions. This Special Issue will provide an open platform for reporting and sharing the latest advances in this field.

Deadline for manuscript submissions:

closed (30 April 2022)





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Message from the Editor-in-Chief

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